Abstracts

A New On-Wafer Large-Signal Waveform Measurement System with 40 GHz Harmonic Bandwidth

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F. van Raay and G. Kompa. "A New On-Wafer Large-Signal Waveform Measurement System with 40 GHz Harmonic Bandwidth." 1992 MTT-S International Microwave Symposium Digest 92.3 (1992 Vol. III [MWSYM]): 1435-1438.

A novel on-wafer large-signal waveform measurement system with 40 GHz harmonic frequency range using a microwave transition analyzer is presented. Potential applications are illustrated by the measurement of the harmonic amplitude and phase spectra of the reflection and transmission response of a 0.3 µm InGaAs pseudomorphic HEMT under X-band sinusoidal stimulus.

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